Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/005,259	HAYASHI ET AL.	
	Examiner	Art Unit	
	Edwin A. León	2833	

ISSUE CLASSIFICATION

ORIGINAL CLASS	ORIGINAL SUBCLASS	CROSS REFERENCE(S) CLASS	CROSS REFERENCE(S) SUBCLASS (ONE SUBCLASS PER BLOCK)
313	27		

INTERNATIONAL CLASSIFICATION

H	0	1	J	7/24
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Edwin A. Leon (Assistant Examiner) 7/1/06 (Date)	P. AUSTIN BRADLEY SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800	Total Claims Allowed: 6
(Legal Instruments Examiner) 7/10/06 (Date)	(Primary Examiner) 7/3/06 (Date)	O.G. Print Claim(s): 1 / O.G. Print Fig.: 1

☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47

Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		31		61		91		121		151		181
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	11		41		71		101		131		161		191
	12		42		72		102		132		162		192
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	14		44		74		104		134		164		194
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	30		60		90		120		150		180		210